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QUERY CONTROL FORM			RTIS USE ONLY	
Application No.	<u>101005,689</u>	Prepared by	<u>N.H.</u>	Tracking Number
Examiner-GAU	<u>Zarnela - 2829</u>	Date	<u>1-29-04</u>	Week Date
		No. of queries	<u>1</u>	<u>05884744</u>
				<u>01/05/04</u>
				<u>IFW</u>

JACKET

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|----------------------|------------------------|--------------------|----------------|
| a. Serial No. | f. Foreign Priority | k. Print Claim(s) | p. PTO-1449 |
| b. Applicant(s) | g. Disclaimer | l. Print Fig. | q. PTOL-85b |
| c. Continuing Data | h. Microfiche Appendix | m. Searched Column | r. Abstract |
| d. PCT | i. Title | n. PTO-270/328 | s. Sheets/Figs |
| e. Domestic Priority | j. Claims Allowed | o. PTO-892 | t. Other |

SPECIFICATION

- a. Page Missing
- b. Text Continuity
- c. Holes through Data
- d. Other Missing Text
- e. Illegible Text
- f. Duplicate Text
- g. Brief Description
- h. Sequence Listing
- i. Appendix
- j. Amendments
- k. Other

MESSAGE

PTO-1449: Please either initial or line through citations. Copy provided for reference.

CLAIMS

- a. Claim(s) Missing
- b. Improper Dependency
- c. Duplicate Numbers
- d. Incorrect Numbering
- e. Index Disagrees
- f. Punctuation
- g. Amendments
- h. Bracketing
- i. Missing Text
- j. Duplicate Text
- k. Other

C Thank you

initials N.H.

RESPONSE

initials

**INFORMATION DISCLOSURE CITATION
(37 CFR 1.97)**

Application Number
Filing Date
First Named Inventor Ruttent
Group Art Unit
Examiner Name
Attorney Docket US 018180

110/005689
11/08/01
11026 U.S. PRO

U.S. PATENT DOCUMENTS

Examiner's Initials	Cite No.	Patent Number	Date	Name	Class	Sub-Class	Filing Date, If Approp.
	AA	6,075,373	13 June 2000	Iino			
	AB	6,169,410 B1	2 January 2001	Grace et al.			
	AC	(copending application) "PRECONDITIONED INTEGRATED CIRCUIT FOR INTEGRATED CIRCUIT TESTING"		Ruttent			(concurrent)
	AD						
	AE						
	AF						
	AG						
	AH						

FOREIGN PATENT DOCUMENTS

Examiner's Initials	Cite No.	Patent Number	Date	Country	Class	Sub-Class	Translation	
							Yes	No
AJ	EP 0 755 071 A2	18 July 1996	Europe					
AJ								
AK								
AL								
AM								

Examiner's Initials	Cite No.	Other (Include Author, Title, Date, Pertinent Pages, Etc.)
	AN	"Introducing WOW Technology", http://www.formfactor.com/about/wow/wow_pg2.html
	AO	"Introducing WOW Technology", http://www.formfactor.com/about/wow/wow_pg5.html
	AP	"Focus on FormFactor", THE FINAL TEST REPORT, Vol. 12, No. 09, September 2001, Ikonix Corp. P.O. Box 1938, Lafayette, CA 94549-1938
	AQ	"Flip-Chip Bonding on 6-um Pitch using Thin-Film Microspring Technology", Donald L. Smith et al., Xerox Palo Alto Research Center, Proceedings, 48 th Electronic Components and Technology Conference, IEEE, May 1998.
	AR	

Examiner	Date Considered
Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to the Applicant.	